ASMA Ver.	0. 7. 0 zvector- e7-0	02-VGBM (Zv	ector E7 V	RI-a instruc	tion)	12 Feb 2025 14: 28: 07 Page 3
LOC	OBJECT CODE	ADDR1	ADDR2	STMI		
				108 *	Low core PSWs	********************************
00000000		00000000	00001DEF	110 ZVE7TS		Low core addressability
		00000140	00000000	112 113 SVOLDP	SW EQU ZVE7TST+X' 140'	z/Arch Supervisor call old PSW
00000000 000001A0 000001A8	00000001 80000000 00000000 00000200	0000000	000001A0	115 116 117	ORG ZVE7TST+X' 1AO' DC X' 00000001800000 DC AD(BEGIN)	z/Architecure RESTART PSW
000001B0 000001D0 000001D8	00020001 80000000 00000000 0000DEAD	000001B0	000001D0	119 120 121	ORG ZVE7TST+X' 1DO' DC X' 00020001800000 DC AD(X' DEAD')	z/Architecure PROGRAM CHECK PSW
					, —— <i>,</i>	
000001E0		000001E0	00000200	123	ORG ZVE7TST+X' 200'	Start of actual test program
				126 * 127 ***** 128 * 129 * Arc	The actual "ZVE ************************************	**************************************
				130 * Reg 131 * 132 * R0 133 * R1 134 * R5	- 4 (work)	ble - current test base
					-R7 (work) First base registe	er
				138 * R1 139 * R1 140 * R1	0 Third base registe 1 E7TEST call return	\mathbf{r}
				141 * R1 142 * R1 143 * R1	3 (work) 4 Subroutine call	no call or work
				143 * K1 144 * 145 *****	J	**************************************
00000200 00000200 00000200		00000200 00001200 00002200		147 148 149	USING BEGIN, R8 USING BEGIN+4096, R9 USING BEGIN+8192, R10	FIRST Base Register SECOND Base Register THIRD Base Register
00000200 00000202 00000204	0580 0680 0680			151 BEGIN 152 153	BALR R8, 0 BCTR R8, 0 BCTR R8, 0	Initalize FIRST base register Initalize FIRST base register Initalize FIRST base register
	4190 8800 4190 9800		00000800 00000800	155 156 157	LA R9, 2048(, R8) LA R9, 2048(, R9)	Initalize SECOND base register Initalize SECOND base register

LOC	OBJECT CODE	ADDR1	ADDR2	STMI			
				199 ******	****	*******	**********
				200 *		Do tests in the I	E7TESTS table
				201 ******	****	* * * * * * * * * * * * * * * * * * * *	**********
	7000 0000		00000400	202	_	DAG A (FETTERS)	
000002D0	58C0 8290		00000490	203	L	R12, = $A(E7TESTS)$	get table of test addresses
		000002D4	00000001	204 205 NEXTE6	EOH	*	
000002D4	5850 C000	000002D4	00000001	205 NEATEG	EQU L	R5, 0(0, R12)	get test address
000002D4	1255		0000000	207	LTR	R5, R5	have a test?
000002DA			00000318	208	BZ	ENDTEST	done?
000000	1700 0110		000000	209			
000002DE		00000000		210	USING	E7TEST, R5	
				211			
000002DE			00000004	212	LH	RO, TNUM	save current test number
000002E2	5000 8E04		00001004	213	ST	RO, TESTING	for easy reference
00000000	50 D 0 5000		0000000	214	т	D44 ECUD	
000002E6			0000000	215	L	R11, TSUB	get address of test routine
000002EA	05BB			216 217	BALR	R11, R11	do test
000002EC	E310 5020 0014		00000020	218	LGF	R1, READDR	get address of expected result
000002EC		00000030	00000020	219	CLC	V10UTPUT, O(R1)	valid?
000002F8		0000000	00000304	220	BNE	FAI LMSG	no, issue failed message
				221		 -	-,
000002FC			0000004	222	LA	R12, 4(0, R12)	next test address
00000300	47F0 80D4		000002D4	223	В	NEXTE6	

ASMA Ver.	0. 7. 0 zvector- e7- 0	2-VGBM (Zv	ector E7	VRI-a i	nstructi	on)		12 Feb 2025 14: 28: 07 Page 9
LOC	OBJECT CODE	ADDR1	ADDR2	STM				
				330 331 332	******* * *****	****** Norma	**************************************	**************************************
00000458	00020001 80000000			334	EOJPSW	DC	OD' O' , X' 0002000	018000000', AD(0)
00000468	B2B2 8258		00000458	336	EOJ	LPSWE	EOJPSW	Normal completion
00000470	00020001 80000000			338	FAILPSW	DC	0D' 0' , X' 0002000	018000000', AD(X'BAD')
	B2B2 8270		00000470		FAI LTEST			Abnormal termination
				343	******* * *****			**************************************
00000484 00000488	0000000			346 347	CTLRO	DS DS	F F	CRO
	0000000						_	Ittanala maal
0000048C 0000048C 00000490 00000494	00000040 00001D6C 00000001			349 350 351 352		LTORG	, =F' 64' =A(E7TESTS) =F' 1'	Literals pool
00000498 0000049A	0000 005F			353 354 355			=H' 0' =AL2(L' MSGMSG)	
		00000	0000000	356 357			constants	
		00000400 00001000 00010000 00100000		360 361	PAGE K64	EQU EQU EQU EQU	1024 (4*K) (64*K) (K*K)	One KB Size of one page 64 KB 1 MB
		AABBCCDD 000000DD	00000001 00000001		REG2PATT REG2LOW		X' AABBCCDD' X' DD'	Polluted Register pattern (last byte above)

ASMA Ver.	0. 7. 0 zvector-e7	'- 02- VGBM (Zv	ector E7	VRI-a i	nstructi	on)		12 Feb 2025 14: 28: 07 Page	12
LOC	OBJECT CODE	ADDR1	ADDR2	STMT					

				408 409	******	E7TES *****	T DSECT *********	***********	
					E7TEST	DSECT	•		
00000000 0000004	00000000 0000				TSUB TNUM	DC DC	A(0) H' 00'	pointer to test Test Number	
0000006	00			414		DC	X' 00'		
0000007	0000			415 416		DC	XL2' 00'	i2 used	
0000009	40404040 40404040 00000000				OPNAME V2ADDR	DC DC	CL8' ' A(0)	E6 name address of v2 source	
0000018	0000000			419	V3ADDR	DC	A(0)	address of v3 source	
0000001C 00000020	00000000 0000000				RELEN READDR	DC DC	A(0) A(0)	RESULT LENGTH result (expected) address	
0000028	0000000 00000000			422	V10UTPUT	DS	FD	gap V1 Output	
	0000000 00000000 0000000 00000000			424	VIUUIPUI	DS DS	XL16 FD	vi output gap	
				425 426	*	test	routine will	be here (from VRI-a macro)	
				427	*			De 11011 (11011 VIII & 1111010)	
				428 429		10110	wed by EXPECTED RES	ULT	
000010B8		00000000	00001DEF	431 432	ZVE7TST	CSECT DS	, OF		

				435 436	* Ma (*******	cros t *****	o help build	test tables **************	
				438	*				
					* macro	to gen	erate individ	ual test	
				441		MACRO			
				442 443	*	VRI_A	&INST, &I2	&INST - VRI-a instruction under test	
				444				&i 2 - i 2 mask field	
				445 446			&TNUM		
				447 448	&TNUM	SETA	&TNUM+1		
				449		DS	OFD		
				450 451		USING	↑, K 5	base for test data and test routine	
					T&TNUM	DC DC	A(X&TNUM) H' &TNUM	address of test routine test number	
				454		DC	X' 00'		
				455 456		DC DC	XL2' &I 2' CL8' &I NST'	i2 instruction name	
				457		DC	A(RE&TNUM+16)		

address of v3 source

result length

gap V1 output

result address

A(RE4+32)

A(16)

FD

XL16

A(RE4)

DC

DC

DC

DS

DS

602 +

603 +

605+

604+REA4

606+V104

L₀C

00001158

00001160

00001168

00001170

00001170

00001176

0000117C

00001182

00001184

00001184

00001184

0000118C

00001198

00001198

00001198

0000119C

0000119E

0000119F

000011A1

000011AC

000011B0

000011B4

000011B8 000011C0

000011C8

000011D0

000011D8

000011E0

000011E0

000011E6

000011EC

000011F2

000011F4

000011F4

000011F4

000011FC

00001208

00001208

00001208

0000120C

0000120E

0000120F

00001211

0000121C

00001220

00001224

00001228

00001230

00001238

00001240

OBJECT CODE

0000000 00000000

0000000 00000000

0000000 00000000

E760 8E98 0806

E760 0001 0844

E760 5030 080E

0000000 00000000

0000000 000000FF

E5C7C2D4 40404040

0000000 00000000

0000000 00000000

0000000 00000000

0000000 00000000

E760 8E98 0806

E760 0002 0844

E760 5030 080E

0000000 00000000

0000000 0000FF00

E5C7C2D4 40404040

0000000 00000000

0000000 00000000

0000000 00000000

07FB

000011E0

00001204

00001214

00000010

000011F4

0003

0002

07FB

00001250

00001274

00001284

0000010

00001264

0004

0004

00

FD

gap

DS

657+

658 + *

00001328

07FB

00001410

00001434

00001444

00000010

00001424

E5C7C2D4 40404040

0000000 00000000

0000000 00000000

0000000 00000000 0000000 00000000

0008

0040

00

LOC

00001330

00001330

00001336

0000133C

00001342

00001344

00001344

00001344

0000134C

00001358

00001358

00001358

0000135C

0000135E

0000135F

00001361

0000136C

00001370

00001374

00001378

00001380

00001388

00001390

00001398

000013A0

000013A0

000013A6

000013AC

000013B2

000013C8

000013C8

000013C8

000013CC

000013CE

000013CF

000013D1

000013DC

000013E0

000013E4

000013E8

000013F0

000013F8

00001400

00001408

OBJECT CODE

E760 8E98 0806

E760 0010 0844

E760 5030 080E

0000000 00000000

000000FF 00000000

E5C7C2D4 40404040

0000000 00000000

0000000 00000000

0000000 00000000

0000000 00000000

E760 8E98 0806

E760 0020 0844

E760 5030 080E

07FB

000013A0

000013C4

000013D4

00000010

000013B4

0007

0020

00

ASMA Ver. 0.7.0 zvector-e7-02-VGBM (Zvector E7 VRI-a instruction)

ADDR1

00001358

000013C8

ADDR2

00001098

00001318

00001098

00001388

00001098

STM

659 + X6

660 +

661+

662 +

663+

665 +

666

667 668

669 +

670+

672 +

673 +

674 +

675+

676+

677 +

678+

680 +

682 +

685 +

686+

687 +

688+

690 +

694+

695 +

697 +

698 +

699+

700+

701 +

702 +

703+

705+

707+

704+REA8

706+V108

691

689+RE7

683+*

684+X7

679+REA7

681+V107

671+T7

664+RE6

DS

VL

VST

BR

DC

DC

DS

DC

DC

DC

DC

DC

DC

DC

DC

DC

DS

DS

DS

DS

VL

VGBM

VST

BR

DC

DC

DS

DC

DC

DC

DC

DC

DC

DS

DS

DROP

DROP

V22, V1FUDGE

VGBM V22, X' 0010'

R11

0F

R5

VRI_A VGBM 0020

OFD

A(X7)

H' 7'

X' 00'

A(16)

FD

FD

 $\mathbf{0F}$

R11

0F

R5

OFD

XL16

A(RE7)

XL2' 0020'

CL8' VGBM

A(RE7+16)

A(RE7+32)

V22, V1FUDGE

V22, X' 0020'

V22, V107

i 2

gap

USING *, R5

V22, V106

USING *, R5 A(X8)696 + T8DC DC H' 8' DC X' 00'

XL2' 0040' i 2 CL8' VGBM instruction name A(RE8+16)address of v2 source A(RE8+32)address of v3 source A(16)

result length result address gap V1 output

gap

test number

base for test data and test routine

address of test routine

XL16 DS FD

FD

A(RE8)

708+* 709+X8 DS 0F **VL** 710+

V22, V1FUDGE

00001410 E760 8E98 0806 00001410

759+X10

760+

761+

762+

00001098

000014D8

DS

VL

VST

 $\mathbf{0F}$

VGBM V22, X' 0100'

V22, V1FUDGE

V22, V1010

test instruction (dest is a source)

save v1 output

000014F0

000014F0

000014F6

000014FC

E760 8E98 0806

E760 0100 0844

E760 5030 080E

ASMA Ver.	0. 7. 0 zvector- e7-0	02-VGBM (Zv	ector E7 VI	RI-a instructi	on)		12 Feb 2025 14: 28: 07 Page 19
LOC	OBJECT CODE	ADDR1	ADDR2	STMI			
	0000000 000000FF			763+ 764+RE10 765+ 766	BR DC DROP DC	R11 OF R5 XL16' 00000000 000	return xl 16 expected result 0000FF 00000000 00000000' expected mask
0000150C	0000000 00000000			767			
00001518				768 769+	VRI_A DS	VGBM, 0200 OFD	
00001518	00001560 000B	00001518		770+ 771+T11 772+	USI NG DC DC		base for test data and test routine address of test routine test number
0000151F 00001521	00 0200 E5C7C2D4 40404040			773+ 774+ 775+	DC DC DC	X' 00' XL2' 0200' CL8' VGBM	i2 instruction name
00001530 00001534	00001584 00001594 00000010			776+ 777+ 778+	DC DC DC	A(RE11+16) A(RE11+32) A(16)	address of v2 source address of v3 source result length
00001548	00000000 00000000 0000000 00000000			779+REA11 780+ 781+V1011	DC DS DS	A(RE11) FD XL16	result address gap V1 output
00001558	00000000 00000000			782+ 783+*	DS	FD	gap
00001560 00001560 00001566	E760 8E98 0806 E760 0200 0844		00001098	784+X11 785+ 786+	DS VL VGBM		test instruction (dest is a source)
00001572 00001574	E760 5030 080E 07FB		00001548	787+ 788+ 789+RE11	VST BR DC	V22, V1011 R11 OF	save v1 output return xl16 expected result
00001574 00001574 0000157C	00000000 0000FF00 00000000 00000000			790+ 791	DROP DC	R5 XL16' 00000000 000	00FF00 00000000 00000000' expected mask
				792 793		VGBM, 0400	
00001588 00001588 00001588 0000158C	000015D0 000C	00001588		794+ 795+ 796+T12 797+	DS USING DC DC	OFD *, R5 A(X12) H' 12'	base for test data and test routine address of test routine test number
0000158E 0000158F 00001591	00 0400 E5C7C2D4 40404040			798+ 799+ 800+	DC DC DC	X' 00' XL2' 0400' CL8' VGBM	i2 instruction name
000015A0 000015A4	000015F4 00001604 00000010 000015E4			801+ 802+ 803+ 804+REA12	DC DC DC DC	A(RE12+16) A(RE12+32) A(16) A(RE12)	address of v2 source address of v3 source result length result address
000015B0 000015B8	00000000 00000000 00000000 00000000 000000			805+ 806+V1012	DS DS	FD XL16	gap V1 output
	00000000 00000000			807+ 808+* 809+X12	DS DS	FD OF	gap
000015D0 000015D6	E760 8E98 0806 E760 0400 0844 E760 5030 080E		00001098 000015B8	810+ 811+ 812+	VL VGBM VST	V22, V1FUDGE	test instruction (dest is a source) save v1 output
	07FB		30001000	813+ 814+RE12	BR DC	R11 OF	return xl16 expected result

DC

866

XL16' 000000FF 00000000 00000000 00000000' expected mask

000000FF 00000000

000016C4

ASMA Ver	0. 7. 0 zvector-e7-0	02-VGBM (Zv	ector E7 V	/RI-a instructi	on)		12 Feb 2025 14: 28: 07 Page 21
LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000016CC	00000000 00000000						
				867			
				868		VGBM, 2000	
000016D8				869+	DS	OFD	
000016D8	000047700	000016D8		870+	USING		base for test data and test routine
000016D8	00001720			871+T15	DC	A(X15)	address of test routine
000016DC 000016DE	000F 00			872+ 873+	DC DC	H' 15' X' 00'	test number
000016DE	2000			874+	DC	XL2' 2000'	i 2
000016E1	E5C7C2D4 40404040			875+	DC	CL8' VGBM	instruction name
000016EC	00001744			876+	DC	A(RE15+16)	address of v2 source
000016F0	00001754			877+	DC	A(RE15+32)	address of v3 source
000016F4	00000010			878+	DC	A(16)	result length
000016F8	00001734			879+REA15	DC	A(RE15)	result address
00001700 00001708	00000000 00000000			880+ 881+V1015	DS DS	FD XL16	gap V1 output
00001708	00000000 00000000 0000000 00000000			001+11013	אמ	ALIO	V1 output
00001718				882+	DS	FD	gap
00001.10				883+*			5 -r
00001720				884+X15	DS	OF	
00001720	E760 8E98 0806		00001098	885+	VL	V22, V1FUDGE	
00001726	E760 2000 0844		00001700	886+	VGBM		test instruction (dest is a source)
0000172C 00001732	E760 5030 080E 07FB		00001708	887+ 888+	VST BR	V22, V1015 R11	save v1 output return
00001732	U/FB			889+RE15	DC DC	OF	xl16 expected result
00001734				890+	DROP	R5	Allo expected result
	AAAATTAA AAAAAAA						
00001734				891	DC	XL16' 0000FF00 000	00000 00000000 00000000' expected mask
00001734 0000173C					DC	XL16' 0000FF00 000	000000 00000000 00000000' expected mask
				892			000000 00000000 00000000' expected mask
0000173C				892 893	VRI_A	VGBM, 4000	000000 00000000 00000000' expected mask
0000173C 00001748		00001748		892 893 894+	VRI_A DS	VGBM, 4000 OFD	
0000173C	0000000 00000000	00001748		892 893	VRI_A DS USING DC	VGBM, 4000 OFD	base for test data and test routine address of test routine
0000173C 00001748 00001748 0000174C	0000000 00000000 00001790 0010	00001748		892 893 894+ 895+ 896+T16 897+	VRI_A DS USING DC DC	VGBM, 4000 OFD *, R5 A(X16) H' 16'	base for test data and test routine
0000173C 00001748 00001748 0000174C 0000174E	0000000 00000000 00001790 0010 00	00001748		892 893 894+ 895+ 896+T16 897+ 898+	VRI_A DS USING DC DC DC	VGBM, 4000 OFD *, R5 A(X16) H' 16' X' 00'	base for test data and test routine address of test routine test number
0000173C 00001748 00001748 0000174C 0000174E 0000174F	00000000 00000000 00001790 0010 00 4000	00001748		892 893 894+ 895+ 896+T16 897+ 898+ 899+	VRI_A DS USING DC DC DC DC	VGBM 4000 OFD *, R5 A(X16) H' 16' X' 00' XL2' 4000'	base for test data and test routine address of test routine test number
0000173C 00001748 00001748 0000174C 0000174E 0000174F 00001751	00000000 00000000 00001790 0010 00 4000 E5C7C2D4 40404040	00001748		892 893 894+ 895+ 896+T16 897+ 898+ 899+ 900+	VRI_A DS USING DC DC DC DC DC	VGBM, 4000 OFD *, R5 A(X16) H' 16' X' 00' XL2' 4000' CL8' VGBM	base for test data and test routine address of test routine test number i2 instruction name
0000173C 00001748 00001748 0000174C 0000174E 0000174F 00001751 0000175C	00000000 00000000 00001790 0010 00 4000 E5C7C2D4 40404040 000017B4	00001748		892 893 894+ 895+ 896+T16 897+ 898+ 899+ 900+ 901+	VRI_A DS USING DC DC DC DC DC DC	VGBM, 4000 OFD *, R5 A(X16) H' 16' X' 00' XL2' 4000' CL8' VGBM A(RE16+16)	base for test data and test routine address of test routine test number
0000173C 00001748 00001748 0000174C 0000174E 00001751 0000175C 00001760 00001764	00000000 00000000 00001790 0010 00 4000 E5C7C2D4 40404040 000017B4 000017C4 00000010	00001748		892 893 894+ 895+ 896+T16 897+ 898+ 899+ 900+ 901+ 902+ 903+	VRI_A DS USING DC DC DC DC DC DC DC DC	VGBM, 4000 OFD *, R5 A(X16) H' 16' X' 00' XL2' 4000' CL8' VGBM' A(RE16+16) A(RE16+32) A(16)	base for test data and test routine address of test routine test number i2 instruction name address of v2 source address of v3 source result length
0000173C 00001748 00001748 0000174C 0000174E 00001751 0000175C 00001760 00001764 00001768	00000000 00000000 00001790 0010 00 4000 E5C7C2D4 40404040 000017B4 000017C4 00000010 000017A4	00001748		892 893 894+ 895+ 896+T16 897+ 898+ 899+ 900+ 901+ 902+ 903+ 904+REA16	VRI_A DS USING DC DC DC DC DC DC DC DC DC	VGBM, 4000 OFD *, R5 A(X16) H' 16' X' 00' XL2' 4000' CL8' VGBM A(RE16+16) A(RE16+32) A(16) A(RE16)	base for test data and test routine address of test routine test number i2 instruction name address of v2 source address of v3 source result length result address
0000173C 00001748 00001748 0000174C 0000174E 00001751 0000175C 00001760 00001764 00001768 00001770	00000000 00000000 00001790 0010 00 4000 E5C7C2D4 40404040 00001784 000017C4 0000010 000017A4 00000000 00000000	00001748		892 893 894+ 895+ 896+T16 897+ 898+ 899+ 900+ 901+ 902+ 903+ 904+REA16 905+	VRI_A DS USING DC	VGBM, 4000 OFD *, R5 A(X16) H' 16' X' 00' XL2' 4000' CL8' VGBM A(RE16+16) A(RE16+32) A(16) A(RE16) FD	base for test data and test routine address of test routine test number i2 instruction name address of v2 source address of v3 source result length result address
0000173C 00001748 00001748 0000174C 0000174E 00001751 0000175C 00001760 00001764 00001768 00001770 00001778	00000000 00000000 00001790 0010 00 4000 E5C7C2D4 40404040 00001784 000001704 000001704 000001704 00000000 00000000 00000000 00000000	00001748		892 893 894+ 895+ 896+T16 897+ 898+ 899+ 900+ 901+ 902+ 903+ 904+REA16	VRI_A DS USING DC DC DC DC DC DC DC DC DC	VGBM, 4000 OFD *, R5 A(X16) H' 16' X' 00' XL2' 4000' CL8' VGBM A(RE16+16) A(RE16+32) A(16) A(RE16)	base for test data and test routine address of test routine test number i2 instruction name address of v2 source address of v3 source result length
0000173C 00001748 00001748 0000174C 0000174F 00001751 0000175C 00001760 00001764 00001768 00001770 00001778 00001780	00000000 00000000 00001790 0010 00 4000 E5C7C2D4 40404040 00001784 0000017C4 00000010 000017A4 00000000 00000000 00000000 00000000 00000000	00001748		892 893 894+ 895+ 896+T16 897+ 898+ 899+ 900+ 901+ 902+ 903+ 904+REA16 905+ 906+V1016	VRI _A DS USI NG DC	VGBM, 4000 OFD *, R5 A(X16) H' 16' X' 00' XL2' 4000' CL8' VGBM A(RE16+16) A(RE16+32) A(16) A(RE16) FD XL16	base for test data and test routine address of test routine test number i2 instruction name address of v2 source address of v3 source result length result address gap V1 output
0000173C 00001748 00001748 0000174C 0000174E 00001751 0000175C 00001760 00001764 00001768 00001770 00001778	00000000 00000000 00001790 0010 00 4000 E5C7C2D4 40404040 00001784 000001704 000001704 000001704 00000000 00000000 00000000 00000000	00001748		892 893 894+ 895+ 896+T16 897+ 898+ 899+ 900+ 901+ 902+ 903+ 904+REA16 905+	VRI_A DS USING DC	VGBM, 4000 OFD *, R5 A(X16) H' 16' X' 00' XL2' 4000' CL8' VGBM A(RE16+16) A(RE16+32) A(16) A(RE16) FD	base for test data and test routine address of test routine test number i2 instruction name address of v2 source address of v3 source result length result address
0000173C 00001748 00001748 0000174C 0000174E 00001751 0000175C 00001760 00001764 00001768 00001770 00001778 00001780 00001780	00000000 00000000 00001790 0010 00 4000 E5C7C2D4 40404040 000017C4 0000017C4 0000017C4 00000000 00000000 00000000 00000000 00000000	00001748		892 893 894+ 895+ 896+T16 897+ 898+ 899+ 900+ 901+ 902+ 903+ 904+REA16 905+ 906+V1016	VRI_A DS USING DC	VGBM, 4000 OFD *, R5 A(X16) H' 16' X' 00' XL2' 4000' CL8' VGBM A(RE16+16) A(RE16+32) A(16) A(RE16) FD XL16 FD	base for test data and test routine address of test routine test number i2 instruction name address of v2 source address of v3 source result length result address gap V1 output
0000173C 00001748 00001748 0000174C 0000174F 00001751 0000175C 00001760 00001768 00001770 00001770 00001778 00001780 00001790 00001790	00000000 00000000 00001790 0010 00 4000 E5C7C2D4 40404040 00001784 0000017C4 00000170 000017A4 00000000 00000000 00000000 00000000 00000000	00001748	00001098	892 893 894+ 895+ 896+T16 897+ 898+ 899+ 900+ 901+ 902+ 903+ 904+REA16 905+ 906+V1016	VRI _A DS USI NG DC	VGBM, 4000 OFD *, R5 A(X16) H' 16' X' 00' XL2' 4000' CL8' VGBM A(RE16+16) A(RE16+32) A(16) A(RE16) FD XL16 FD V22, V1FUDGE	base for test data and test routine address of test routine test number i2 instruction name address of v2 source address of v3 source result length result address gap V1 output gap
0000173C 00001748 00001748 0000174C 0000174F 00001751 0000175C 00001760 00001764 00001768 00001770 00001778 00001780 00001790 00001790 00001796	00000000 00000000 00001790 0010 00 4000 E5C7C2D4 40404040 00001784 000017C4 00000170 000017A4 00000000 00000000 00000000 00000000 00000000	00001748		892 893 894+ 895+ 896+T16 897+ 898+ 899+ 900+ 901+ 902+ 903+ 904+REA16 905+ 906+V1016 907+ 908+* 909+X16 910+ 911+	VRI_A DS USING DC	VGBM, 4000 OFD *, R5 A(X16) H' 16' X' 00' XL2' 4000' CL8' VGBM A(RE16+16) A(RE16+32) A(16) A(RE16) FD XL16 FD V22, V1FUDGE V22, X' 4000'	base for test data and test routine address of test routine test number i2 instruction name address of v2 source address of v3 source result length result address gap V1 output gap test instruction (dest is a source)
0000173C 00001748 00001748 0000174C 0000174F 00001751 0000175C 00001760 00001764 00001768 00001770 00001778 00001780 00001790 00001790 00001796 00001796 00001796	00000000 00000000 00001790 0010 00 4000 E5C7C2D4 40404040 00001784 000017C4 00000010 000017A4 00000000 00000000 00000000 00000000 00000000	00001748	00001098 00001778	892 893 894+ 895+ 896+T16 897+ 898+ 899+ 900+ 901+ 902+ 903+ 904+REA16 905+ 906+V1016 907+ 908+* 909+X16 910+ 911+ 912+	VRI _A DS USI NG DC DC DC DC DC DC DC DC DC VB DC	VGBM, 4000 0FD *, R5 A(X16) H' 16' X' 00' XL2' 4000' CL8' VGBM A(RE16+16) A(RE16+32) A(16) A(RE16) FD XL16 FD OF V22, V1FUDGE V22, X' 4000' V22, V1016	base for test data and test routine address of test routine test number i2 instruction name address of v2 source address of v3 source result length result address gap V1 output gap test instruction (dest is a source) save v1 output
0000173C 00001748 00001748 0000174C 0000174F 00001751 0000175C 00001760 00001764 00001770 00001770 00001778 00001780 00001790 00001790 00001790 0000179C 000017A2	00000000 00000000 00001790 0010 00 4000 E5C7C2D4 40404040 00001784 000017C4 00000170 000017A4 00000000 00000000 00000000 00000000 00000000	00001748		892 893 894+ 895+ 896+T16 897+ 898+ 899+ 900+ 901+ 902+ 903+ 904+REA16 905+ 906+V1016 907+ 908+* 909+X16 910+ 911+ 912+ 913+	VRI _A DS USI NG DC DC DC DC DC DC DC DC DC VG DC	VGBM, 4000 0FD *, R5 A(X16) H' 16' X' 00' XL2' 4000' CL8' VGBM A(RE16+16) A(RE16+32) A(16) A(RE16) FD XL16 FD V22, V1FUDGE V22, X' 4000' V22, V1016 R11	base for test data and test routine address of test routine test number i2 instruction name address of v2 source address of v3 source result length result address gap V1 output gap test instruction (dest is a source) save v1 output return
0000173C 00001748 00001748 0000174C 0000174F 00001751 0000175C 00001760 00001764 00001768 00001770 00001778 00001780 00001790 00001790 00001796 00001796 00001796	00000000 00000000 00001790 0010 00 4000 E5C7C2D4 40404040 00001784 000017C4 00000010 000017A4 00000000 00000000 00000000 00000000 00000000	00001748		892 893 894+ 895+ 896+T16 897+ 898+ 899+ 900+ 901+ 902+ 903+ 904+REA16 905+ 906+V1016 907+ 908+* 909+X16 910+ 911+ 912+	VRI _A DS USI NG DC DC DC DC DC DC DC DC DC VB DC	VGBM, 4000 0FD *, R5 A(X16) H' 16' X' 00' XL2' 4000' CL8' VGBM A(RE16+16) A(RE16+32) A(16) A(RE16) FD XL16 FD OF V22, V1FUDGE V22, X' 4000' V22, V1016	base for test data and test routine address of test routine test number i2 instruction name address of v2 source address of v3 source result length result address gap V1 output gap test instruction (dest is a source) save v1 output
0000173C 00001748 00001748 0000174C 0000174E 0000174F 00001751 00001760 00001764 00001768 00001770 00001770 00001780 00001780 00001790 00001790 00001790 00001794 000017A2 000017A4 000017A4	00000000 00000000 0001790 0010 00 4000 E5C7C2D4 40404040 00001784 000017C4 00000170 000017A4 00000000 00000000 00000000 00000000 00000000	00001748		892 893 894+ 895+ 896+T16 897+ 898+ 899+ 900+ 901+ 902+ 903+ 904+REA16 905+ 906+V1016 907+ 908+* 909+X16 910+ 911+ 912+ 913+ 914+RE16	VRI _A DS USI NG DC VGBM VST BR DC	VGBM, 4000 0FD *, R5 A(X16) H' 16' X' 00' XL2' 4000' CL8' VGBM A(RE16+16) A(RE16+32) A(16) A(RE16) FD XL16 FD OF V22, V1FUDGE V22, X' 4000' V22, V1016 R11 OF R5	base for test data and test routine address of test routine test number i2 instruction name address of v2 source address of v3 source result length result address gap V1 output gap test instruction (dest is a source) save v1 output return
0000173C 00001748 00001748 0000174E 0000174F 00001751 0000175C 00001760 00001764 00001770 00001770 00001778 00001780 00001790 00001790 0000179C 000017A2 000017A4 000017A4	00000000 00000000 0001790 0010 00 4000 E5C7C2D4 40404040 00001784 000017C4 00000010 000017A4 00000000 00000000 00000000 00000000 00000000	00001748		892 893 894+ 895+ 896+T16 897+ 898+ 899+ 900+ 901+ 902+ 903+ 904+REA16 905+ 906+V1016 907+ 908+* 909+X16 910+ 911+ 912+ 913+ 914+RE16 915+	VRI _A DS USI NG DC DC DC DC DC DC DC DC DC VGBM VST BR DC DROP	VGBM, 4000 0FD *, R5 A(X16) H' 16' X' 00' XL2' 4000' CL8' VGBM A(RE16+16) A(RE16+32) A(16) A(RE16) FD XL16 FD OF V22, V1FUDGE V22, X' 4000' V22, V1016 R11 OF R5	base for test data and test routine address of test routine test number i2 instruction name address of v2 source address of v3 source result length result address gap V1 output gap test instruction (dest is a source) save v1 output return xl16 expected result

	2,,,,,	,			,		
LOC	OBJECT CODE	ADDR1	ADDR2	STMI			
				918	VRI_A	VGBM, 8000	
000017B8				919+	DS	OFD	
000017B8		000017B8		920+	USING		base for test data and test routine
000017B8	00001800			921+T17	DC	A(X17)	address of test routine
000017BC	0011			922+	DC	H' 17'	test number
000017BE	00 8000			923+ 924+	DC DC	X' 00' XL2' 8000'	i 2
000017BF 000017C1	E5C7C2D4 40404040			924+ 925+	DC DC	CL8' VGBM	instruction name
000017C1	00001824			925+ 926+	DC	A(RE17+16)	address of v2 source
000017CC	00001824			927+	DC	A(RE17+10) A(RE17+32)	address of v2 source
000017D4	00000010			928+	DC	A(16)	result length
000017D8	00001814			929+REA17	DC	A(RE17)	result address
000017E0	0000000 00000000			930+	DS	FD	gap
000017E8	0000000 00000000			931+V1017	DS	XL16	gap V1 output
000017F0	00000000 00000000						
000017F8	00000000 00000000			932+	DS	FD	gap
00001000				933+*	D.C.	O.F.	
00001800	E700 0E00 0000		00001000	934+X17	DS	OF	
00001800 00001806	E760 8E98 0806 E760 8000 0844		00001098	935+ 936+	VL VGBM	V22, V1FUDGE V22, X' 8000'	test instruction (dest is a source)
0000180C	E760 5030 080E		000017E8	930+ 937+	VGBM	V22, X 8000 V22, V1017	test instruction (dest is a source) save v1 output
00001800	07FB		00001710	93 7 + 93 8 +	BR	R11	return
00001812	0715			939+RE17	DC	OF	xl16 expected result
00001814				940+	DROP	R5	ni i onpecceu i coui c
00001814	FF000000 00000000			941	DC	XL16' FF000000 000	00000 00000000 00000000' expected mask
0000181C	0000000 00000000						•
				942		Want noon	
00001000				943		VGBM, FFFF	
00001828 00001828		00001828		944+ 945+	DS USING	OFD * D5	base for test data and test routine
00001828	00001870	00001020		945+ 946+T18	DC	A(X18)	address of test routine
0000182C	0001370			947+	DC	H' 18'	test number
0000182E	00			948+	DC	X' 00'	cese number
0000182F	FFFF			949+	DC	XL2' FFFF'	i 2
00001831	E5C7C2D4 40404040			950 +	DC	CL8' VGBM	instruction name
0000183C	00001894			951+	DC	A(RE18+16)	address of v2 source
00001840	000018A4			952+	DC	A(RE18+32)	address of v3 source
00001844	00000010			953+ 054 PEA10	DC	A(16)	result length
00001848	00001884			954+REA18	DC DC	A(RE18)	result address
00001850 00001858	00000000 00000000 0000000 00000000			955+ 956+V1018	DS DS	FD XL16	gap V1 output
00001860	0000000 0000000			330+11010	טע	VITA	vi oucpuc
00001868	0000000 0000000			957+	DS	FD	gap
0001000				958+*	20		5°F
00001870				959+X18	DS	0F	
00001870	E760 8E98 0806		00001098	960+	VL	V22, V1FUDGE	
00001876	E760 FFFF 0844			961+	VGBM	V22 , X' FFFF'	test instruction (dest is a source)
0000187C	E760 5030 080E		00001858	962+	VST	V22, V1018	save v1 output
00001882	07FB			963+	BR	R11	return
00001884				964+RE18	DC	OF DE	xl16 expected result
00001884 00001884	FFFFFFF FFFFFFF			965+ 966	DROP DC	R5	FFFFF FFFFFFF FFFFFFFF expected mask
0000188C	FFFFFFFF FFFFFFF			300	DC	VEIA LLLLLLL	TEFFE FEFFEFF EFFFFFF expected mask
00001000	TEFFEFF FFFFFF						

LOC	OBJECT CODE	ADDR1	ADDR2	STM			
200	ODGEOT CODE	IDDIVI	IDDIVA				
				968 * 969 * case			
				970 *			
				971		VGBM, 8001	
001898		00004000		972+	DS	OFD	
01898	000019E0	00001898		973+	USING		base for test data and test routine
001898 00189C	000018E0 0013			974+T19 975+	DC DC	A(X19) H' 19'	address of test routine test number
0189E	00			976+	DC	X' 00'	test number
0189F	8001			977+	DC	XL2' 8001'	i 2
0018A1	E5C7C2D4 40404040			978+	DC	CL8' VGBM	instruction name
0018AC	00001904			979+	DC	A(RE19+16)	address of v2 source
0018B0	00001914			980+	DC	A(RE19+32)	address of v3 source
0018B4	0000010			981+	DC	A(16)	result length
0018B8 0018C0	000018F4 00000000 00000000			982+REA19 983+	DC DS	A(RE19) FD	result address
018C8	0000000 0000000			984+V1019	DS DS	XL16	gap V1 output
0018D0	0000000 00000000			331.71010	2.5		Sucpue
0018D8	0000000 00000000			985 +	DS	FD	gap
				986+*			
0018E0	E700 0E00 0000		00001000	987+X19	DS	OF	
0018E0 0018E6	E760 8E98 0806 E760 8001 0844		00001098	988+ 989+	VL VGBM	V22, V1FUDGE V22, X' 8001'	test instruction (dest is a source)
018EC	E760 5030 080E		000018C8	990+	VGDM	V22, X 8001 V22, V1019	test instruction (dest is a source) save v1 output
018F2	07FB		00001000	991+	BR	R11	return
0018F4				992+RE19	DC	0F	xl16 expected result
0018F4				993+	DROP	R5	-
0018F4	FF000000 00000000			994	DC	XL16' FF000000	00000000 00000000 000000FF' expected mask
0018FC	00000000 000000FF			005			
				995 996	VDT A	VGBM, 8181	
001908				997+	DS DS	OFD	
001908		00001908		998+	USING		base for test data and test routine
	00001950	0000100		999+T20	DC	A(X20)	address of test routine
00190C	0014			1000+	DC	H' 20'	test number
00190E	00			1001+	DC	X' 00'	
00190F	8181 E5C7C2D4 40404040			1002+	DC DC	XL2' 8181'	i2
001911 00191C	E5C7C2D4 40404040 00001974			1003+ 1004+	DC DC	CL8' VGBM A(RE20+16)	instruction name address of v2 source
001910	00001974			1004+ 1005+	DC DC	A(RE20+10) A(RE20+32)	address of v2 source
001924	00000010			1006+	DC	A(16)	result length
001928	00001964			1007+REA20	DC	A(RE20)	result address
001930	00000000 00000000			1008+	DS	FD	gap V1 output
001938	00000000 00000000			1009+V1020	DS	XL16	V1 output
001940 001948				1010+	DS	FD	gan
JU 1 I I I O	00000000 00000000			1010+ 1011+*	טע	LD	gap
01950				1011+ 1012+X20	DS	OF	
01950	E760 8E98 0806		00001098	1013+	VL	V22, V1FUDGE	
01956	E760 8181 0844			1014+	VGBM	V22, X' 8181'	test instruction (dest is a source)
00195C	E760 5030 080E		00001938	1015+	VST	V22, V1020	save v1 output
001962	07FB			1016+	BR	R11	return
001964				1017+RE20	DC	OF DE	xl16 expected result
001964 001964	FF000000 000000FF			1018+ 1019	DROP DC	R5	000000FF FF000000 000000FF' expected mask
001964 00196C	FF000000 000000FF			1019	DC	VIIA LLAAAAAA	ooooorr rrooooo ooooorr expected mask
32000							

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LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001A58				1072+	DS	OFD	
00001A58		00001A58		1073+	USING		base for test data and test routine
00001A58	00001AA0	00001A30		1074+T23	DC	A(X23)	address of test routine
00001A5C	00001AA0 0017			1074+123 1075+	DC	H' 23'	test number
00001A5C	0017			1075+ 1076+	DC DC	X' 00'	test number
							: 0
00001A5F	3003			1077+	DC	XL2' 3003'	i 2
00001A61	E5C7C2D4 40404040			1078+	DC	CL8' VGBM	instruction name
00001A6C				1079+	DC	A(RE23+16)	address of v2 source
00001A70	00001AD4			1080+	DC	A(RE23+32)	address of v3 source
00001A74	00000010			1081+	DC	A(16)	result length
00001A78	00001AB4			1082+REA23	DC	A(RE23)	result address
00001A80				1083+	DS	FD	gap V1 output
00001A88	0000000 00000000			1084+V1023	DS	XL16	V1 output
00001A90	0000000 00000000						
00001A98	0000000 00000000			1085+	DS	FD	gap
				1086+*			
00001AA0				1087+X23	DS	OF	
00001AA0	E760 8E98 0806		00001098	1088+	VL	V22, V1FUDGE	
00001AA6	E760 3003 0844		0000100	1089+		V22, X' 3003'	test instruction (dest is a source)
00001AAC	E760 5030 080E		00001A88	1090+	VST	V22, V1023	save v1 output
00001AB2	07FB		000017100	1091+	BR	R11	return
0001AB2	OILD			1092+RE23	DC	0F	xl16 expected result
0001AB4				1092+RE23 1093+	DROP	R5	Al 10 expected Tesult
0001AB4	0000FFFF 00000000			1094	DC		000000 00000000 0000FFFF ownested mosk
				1094	DC	ALIO UUUUFFFF UUU	000000 00000000 0000FFFF' expected mask
DOODTABC	00000000 0000FFFF			1005			
				1095	A/DT A	VCDV 0101	
00004460				1096		VGBM, 3131	
00001AC8		00004460		1097+	DS	OFD	
00001AC8		00001AC8		1098+	USING		base for test data and test routine
00001AC8	00001B10			1099+T24	DC	A(X24)	address of test routine
00001ACC	0018			1100+	DC	H' 24'	test number
00001ACE	00			1101+	DC	X' 00'	
00001ACF	3131			1102+	DC	XL2' 3131'	i 2
00001AD1	E5C7C2D4 40404040			1103+	DC	CL8' VGBM	instruction name
00001ADC	00001B34			1104+	DC	A(RE24+16)	address of v2 source
00001AE0	00001B44			1105+	DC	A(RE24+32)	address of v3 source
00001AE4	0000010			1106+	DC	A(16)	result length
00001AE8	00001B24			1107+REA24	DC	A(RE24)	result address
00001AF0	0000000 0000000			1108+	DS	FD	
00001AF8	0000000 0000000			1100+ 1109+V1024	DS DS	XL16	gap V1 output
00001AF3	0000000 0000000			1100 11067	D O	ALLU	11 oucput
00001B08	0000000 0000000			1110+	DS	FD	don
OOGIDOO				1110+ 1111+*	טט	TU	gap
00001010					DC	OF	
00001B10	EZCO OFOO OCCO		00001000	1112+X24	DS	OF	
00001B10	E760 8E98 0806		00001098	1113+	VL	V22, V1FUDGE	
00001B16	E760 3131 0844		00001150	1114+		V22, X' 3131'	test instruction (dest is a source)
00001B1C	E760 5030 080E		00001AF8	1115+	VST	V22, V1024	save v1 output
00001B22	07FB			1116+	BR	R11	return
00001B24				1117+RE24	DC	0F	xl16 expected result
00001B24				1118+	DROP	R5	
0001B24	0000FFFF 000000FF			1119	DC	XL16' 0000FFFF 000	0000FF 0000FFFF 000000FF' expected mask
00001B2C	0000FFFF 000000FF						r
				1120			
				1121	VRT A	VGBM, 1313	
00001B38				1122+	DS DS	OFD	
00001B38		00001B38		1123+	USING		base for test data and test routine
OOOTIDOO		OCCUIDO		IIWUT	OSTING	, Ito	base for cost data and cost foutflie

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LOC	OBJECT CODE	ADDR1	ADDR2	STM			
00001B38 00001B3C	00001B80 0019			1124+T25 1125+	DC DC	A(X25) H' 25'	address of test routine test number
00001B3E 00001B3F 00001B41	00 1313 E5C7C2D4 40404040			1126+ 1127+ 1128+	DC DC DC	X' 00' XL2' 1313' CL8' VGBM	i2 instruction name
00001B4C 00001B50	00001BA4 00001BB4			1129+ 1130+	DC DC	A(RE25+16) A(RE25+32)	address of v2 source address of v3 source
00001B54 00001B58 00001B60	00000010 00001B94 00000000 00000000			1131+ 1132+REA25 1133+	DC DC DS	A(16) A(RE25) FD	result length result address
00001B00 00001B68 00001B70	0000000 0000000 00000000 00000000			1134+V1025	DS DS	XL16	gap V1 output
00001B78 00001B80	0000000 00000000			1135+ 1136+* 1137+X25	DS	FD OF	gap
00001B80 00001B86	E760 8E98 0806 E760 1313 0844		00001098	1137+A23 1138+ 1139+	DS VL VGBM	V22, V1FUDGE V22, X' 1313'	test instruction (dest is a source)
00001B8C 00001B92	E760 5030 080E 07FB		00001B68	1140+ 1141+	VST BR	V22, V1025 R11	save v1 output return
00001B94 00001B94 00001B94 00001B9C	000000FF 0000FFFF 000000FF 0000FFFF			1142+RE25 1143+ 1144	DC DROP DC		xl16 expected result OFFFF 000000FF 0000FFFF' expected mask
	OUOUUFF OUUUFFF			1145 1146		VGBM, 0770	
00001BA8 00001BA8 00001BA8	00001BF0 001A	00001BA8		1147+ 1148+ 1149+T26 1150+	DS USING DC DC	0FD *, R5 A(X26) H' 26'	base for test data and test routine address of test routine test number
00001BAE 00001BAF 00001BB1	00 0770 E5C7C2D4 40404040			1151+ 1152+ 1153+	DC DC DC	X' 00' XL2' 0770' CL8' VGBM	i2 instruction name
	00001C14			1154+ 1155+ 1156+	DC DC DC	A(RE26+16) A(RE26+32) A(16)	address of v2 source address of v3 source result length
00001BC8 00001BD0 00001BD8	000010 00001C04 00000000 00000000 00000000 00000000			1157+REA26 1158+ 1159+V1026	DC DS DS	A(RE26) FD XL16	result address gap V1 output
00001BD8 00001BE0 00001BE8	0000000 0000000 0000000 00000000 0000000			1160+	DS	FD	gap
00001BF0 00001BF0	E760 8E98 0806		00001098	1161+* 1162+X26 1163+	DS VL	OF V22, V1FUDGE	
00001BF6 00001BFC 00001C02 00001C04	E760 0770 0844 E760 5030 080E 07FB		00001BD8	1164+ 1165+ 1166+ 1167+RE26		V22, X' 0770' V22, V1026 R11 OF	test instruction (dest is a source) save v1 output return xl 16 expected result
00001C04 00001C04 00001C0C	00000000 00FFFFF 00FFFFF 00000000			1168+ 1169	DROP DC	R5	FFFFF 00FFFFFF 00000000' expected mask
00001C18				1170 1171 1172+	VRI_A DS	VGBM, 7007 OFD	
00001C18 00001C18 00001C1C	00001C60 001B	00001C18		1173+ 1174+T27 1175+	USING DC DC		base for test data and test routine address of test routine test number

ASIM VEI.	0. 7. 0 zvector-e7-0	2- VGBM (Zv	ector E7 V	RI-a instructi	on)		12 Feb 2025 14: 28: 07 Page 27
LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001C1E	00			1176+	DC	X' 00'	
00001C1F	7007			1177+	DC	XL2' 7007'	i 2
	E5C7C2D4 40404040			1178+	DC	CL8' VGBM	instruction name
00001C2C	00001C84			1179+	DC	A(RE27+16)	address of v2 source
00001C2C	00001C94			1180+	DC	A(RE27+32)	address of v3 source
00001C30	00000010			1181+	DC	A(16)	result length
00001C34	00001C74			1182+REA27	DC	A(RE27)	result address
00001C38	0000000 00000000			1183+	DS	FD	
00001C40	0000000 0000000			1184+V1027	DS	XL16	gap V1 output
	0000000 0000000			1104+11021	טט	ALIO	vi oucpuc
	0000000 0000000			1185+	DS	FD	dan
00001038	0000000 00000000			1186+*	DЗ	ΓU	gap
00001C60				1187+X27	DC	0F	
	EZEN OENO NONE		00001000		DS VL		
	E760 8E98 0806		00001098	1188+		V22, V1FUDGE	test instruction (dest is a source)
00001C66	E760 7007 0844		00001640	1189+		V22, X' 7007'	test instruction (dest is a source)
	E760 5030 080E		00001C48	1190+	VST	V22, V1027	save v1 output
00001C72	07FB			1191+	BR	R11	return
00001C74				1192+RE27	DC	0F	xl16 expected result
00001C74				1193+			
	00FFFFF 00000000			1194	DC	XL16' 00FFFFFF 000	00000 00000000 00FFFFFF' expected mask
00001C7C	00000000 00FFFFF						
				1195			
				1196		VGBM, 7171	
00001C88				1197+	DS	OFD	
00001C88		00001C88		1198+	USING		base for test data and test routine
00001C88	00001CD0			1199+T28	DC	A(X28)	address of test routine
00001C8C	001C			1200+	DC	H' 28'	test number
00001C8E	00			1201+	DC	X' 00'	
00001C8F	7171			1202+	DC	XL2' 7171'	i 2
00001C91	E5C7C2D4 40404040			1203+	DC	CL8' VGBM	instruction name
00001C9C	00001CF4			1204+	DC	A(RE28+16)	address of v2 source
00001CA0	00001D04			1205+	DC	A(RE28+32)	address of v3 source
00001CA4	0000010			1206+	DC	A(16)	result length
00001CA8	00001CE4			1207+REA28	DC	A(RE28)	result address
00001CB0	00000000 00000000			1208+	DS	FD	gap
00001CB8	0000000 00000000			1209+V1028	DS	XL16	gap V1 output
00001CC0	0000000 00000000						1
00001CC8	0000000 00000000			1210+	DS	FD	gap
				1211+*			
00001CD0				1212+X28	DS	OF	
00001CD0	E760 8E98 0806		00001098	1213+	VL	V22, V1FUDGE	
00001CD6	E760 7171 0844			1214+		V22, X' 7171'	test instruction (dest is a source)
00001CDC	E760 5030 080E		00001CB8	1215+	VST	V22, V1028	save v1 output
00001CE2	07FB			1216+	BR	R11	return
				1217+RE28	DC	0F	xl16 expected result
00001CE4				_~~~			Cipocou Iosui e
00001CE4 00001CE4				1218+	DKOP	KO	-
00001CE4	00FFFFFF 000000FF			1218+ 1219	DROP DC	R5 XL16' 00FFFFFF 000	-
00001CE4 00001CE4	00FFFFFF 000000FF			1218+ 1219	DROP DC		000FF 00FFFFFF 000000FF' expected mask
00001CE4 00001CE4	00FFFFFF 000000FF 00FFFFFF 000000FF			1219			-
00001CE4 00001CE4				1219 1220	DC	XL16' 00FFFFF 000	-
00001CE4 00001CE4 00001CEC				1219 1220 1221	DC VRI_A	VGBM, 1717	-
00001CE4 00001CE4 00001CEC		በበበበ1ሮፑዩ		1219 1220 1221 1222+	DC VRI_A DS	VGBM 1717 OFD	000FF 00FFFFFF 000000FF' expected mask
00001CE4 00001CE4 00001CEC 00001CF8 00001CF8	OOFFFFFF OOOOOOFF	00001CF8		1219 1220 1221 1222+ 1223+	VRI_A DS USING	VGBM 1717 OFD *, R5	000FF 00FFFFFF 000000FF' expected mask base for test data and test routine
00001CE4 00001CE4 00001CEC 00001CF8 00001CF8 00001CF8	00FFFFF 000000FF 00001D40	00001CF8		1219 1220 1221 1222+ 1223+ 1224+T29	VRI_A DS USING DC	VGBM, 1717 OFD *, R5 A(X29)	base for test data and test routine address of test routine
00001CE4 00001CEC 00001CFS 00001CF8 00001CF8 00001CFC	00001D40 001D	00001CF8		1219 1220 1221 1222+ 1223+ 1224+T29 1225+	VRI_A DS USING DC DC	VGBM, 1717 OFD *, R5 A(X29) H' 29'	000FF 00FFFFFF 000000FF' expected mask base for test data and test routine
00001CE4 00001CEC 00001CFS 00001CF8 00001CF8 00001CFC	00FFFFFF 000000FF 00001D40	00001CF8		1219 1220 1221 1222+ 1223+ 1224+T29	VRI_A DS USING DC	VGBM, 1717 OFD *, R5 A(X29)	base for test data and test routine address of test routine

ASMA ver.	0. 7. 0 zvector-e7-02	z-vGBM (Zv	ector E/ V	KI-a instruct	1 on)		12 Feb 2025 14: 28: 07 Page	28
LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
00001D01	E5C7C2D4 40404040			1228+	DC	CL8' VGBM	instruction name	
00001D0C	00001D64			1229+	DC	A(RE29+16)	address of v2 source	
00001D10	00001D74			1230+	DC	A(RE29+32)	address of v3 source	
00001D14	0000010			1231+	DC	A(16)	result length	
00001D18	00001D54			1232+REA29	DC	A(RE29)	result address	
00001D20	00000000 00000000			1233+	DS	FD	gap V1 output	
00001D28	0000000 00000000			1234+V1029	DS	XL16	VI output	
00001D30 00001D38	0000000 0000000 0000000 0000000			1235+	DS	FD	don	
00001036	0000000 0000000			1235+ 1236+*	טע	ГIJ	gap	
00001D40				1237+X29	DS	0F		
00001D40	E760 8E98 0806		00001098	1238+	VL	V22, V1FUDGE		
00001D46	E760 1717 0844			1239+	VGBM	V22, X' 1717'	test instruction (dest is a source)	
00001D4C	E760 5030 080E		00001D28	1240+	VST	V22, V1029	save v1 output	
00001D52	07FB			1241+	BR	R11	return	
00001D54				1242+RE29	DC	0F	xl16 expected result	
00001D54	000000EE 00EEEEE			1243+	DROP	R5	OOFFEEEE OOOOOFF OOFFEEEE	
00001D54	000000FF 00FFFFFF 000000FF 00FFFFFF			1244	DC	XL16 UUUUUUFF	00FFFFFF 000000FF 00FFFFFF' expected mask	
00001D5C	UUUUUTT UUTTTTT			1245				
				1246				
				1247				
00001D64	0000000			1248	DC	F' 0' END 0	OF TABLE	
00001D68	0000000			1249	DC	F' 0'		

DC

DC

DC

DC

A(0)

A(0)

F' 0'

F' 0'

END OF TABLE

END OF TABLE

1286+*

1287+

1288+

1289

1290

1291

00001DE0

00001DE4

00000000

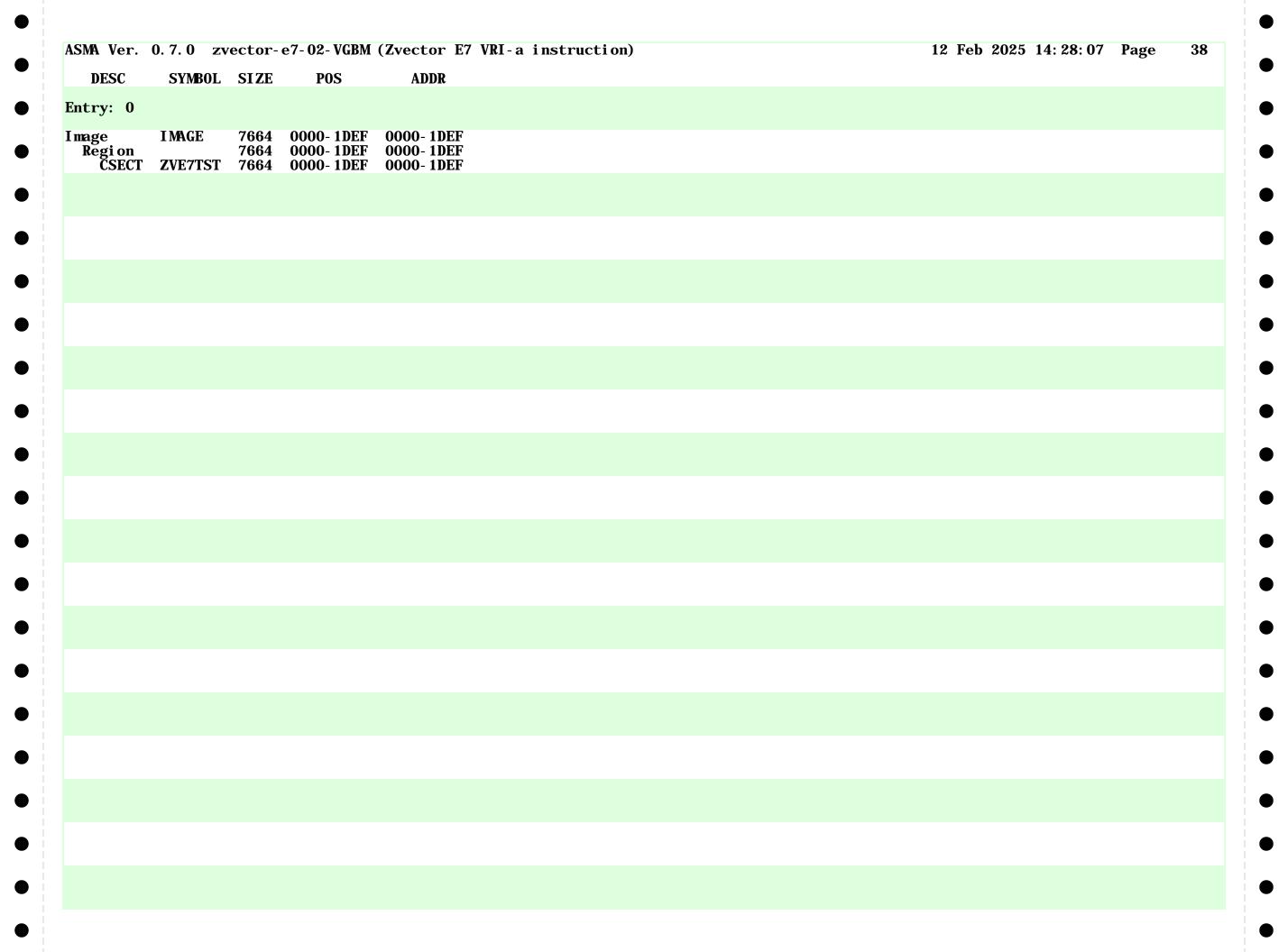
00001DE8 00000000

00001DEC 00000000

ASMA Ver.	0. 7. 0 zvector-e7-0	02-VGBM (Zv	ector E7 V	RI-a instructi	i on)			12 F	eb 2025 14: 2	3: 07	Page	30
LOC	OBJECT CODE	ADDR1	ADDR2	STM								
					Regis	****** ster eq i *****	**************************************					
		00000000 00000001 00000002 00000003 00000005 00000006 00000007 00000008 00000009 0000000A 0000000B 0000000D 0000000D 0000000E	00000001 00000001 00000001 00000001 000000	1297 R0 1298 R1 1299 R2 1300 R3 1301 R4 1302 R5 1303 R6 1304 R7 1305 R8 1306 R9 1307 R10 1308 R11 1309 R12 1310 R13 1311 R14 1312 R15	EQU	0 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15						
				1315 *		****** ster_eqi	**************************************					
		00000000 00000001 00000002 00000003	00000001 00000001 00000001	1316 ******* 1318 V0 1319 V1 1320 V2 1321 V3	EQU EQU EQU EQU	0 1 2 3	***	***	*****	· · · · · · ·	• • • • • •	
		00000004 00000005 00000006 00000007 00000008 00000009	00000001 00000001 00000001 00000001 000000	1322 V4 1323 V5 1324 V6 1325 V7 1326 V8 1327 V9 1328 V10	EQU EQU EQU EQU EQU EQU EQU	4 5 6 7 8 9						
		0000000B 0000000C 0000000D 0000000E 0000000F 00000010	00000001 00000001 00000001 00000001 000000	1329 V11 1330 V12 1331 V13 1332 V14 1333 V15 1334 V16	EQU EQU EQU EQU EQU EQU	11 12 13 14 15 16						
		00000011 00000012 00000013 00000014 00000015	00000001 00000001 00000001 00000001	1335 V17 1336 V18 1337 V19 1338 V20 1339 V21	EQU EQU EQU EQU EQU	17 18 19 20 21						

CVMDOI			I (Zvector F				,						12 Feb				ge :
SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFER												
EGI N	I	00000200	2	151	117	147	148	149									
ΓLRO	F	00000484	4	346	161	162	163	164									
ECNUM	C	00001076	16	397	260	262	268	270									
7TEST	4	0000000	72	411	210												
7TESTS	F	00001D6C	4	1254	203												
DIT	X	0000104A	18	392	261	269											
NDTEST	U	00000318	1	246	208												
)J	Ī	00000468	4	336	196	249											
DJPSW	D	00000458	8	334	336												
AI LCONT	Ū	00000308	Ĭ	236													
AI LED	F	00001000	4	374	238	247											
AI LMSG	Ī	00000304	1	230	220	~ 1 /											
AILPSW	Ď	00000470	8	338	340												
AILTEST	ĭ	00000470	4	340	250												
B0001	Ē	00000180	8	180	184	185	187										
2	X	00000200	2	415	267	100	107										
WAGE	1	00000007	$766\overset{\sim}{4}$	0	201												
	II	0000000	7004	358	359	360	361										
64	U	00010000	1	360	339	300	301										
04 B	U		1														
	U	00100000	1	361	105	970											
SG	C	000003A0	4	296	195	279											
SGCMD	Č	000003EE	9	326	309	310	001										
SGMSG	Ĺ	000003F7	95	327	303	324	301										
SGM/C	Ţ	000003E8	6	324	307												
SGOK	Ţ	000003B6	2	305	302	040											
SGRET	<u> </u>	000003D6	4	320	313	316											
SGSAVE	F	000003DC	4	323	299	320											
EXTE6	U	000002D4	1	205	223	241											
PNAME	C	0000009	8	417	265												
AGE	U	00001000	1	359													
RT3	C	00001060	18	395	261	262	263	269	270	271							
RTI 2	C	00001044	5	385	271												
RTLINE	C	00001008	16	380	387	278											
RTLNG	U	00000042	1	387	277												
RTNAME	C	00001033	8	383	265												
RTNUM	C	00001018	3	381	263												
0	Ü	00000000	Ĭ	1297	111	161	164	184	186	187	188	193	212	213	237	238	276
	Ü	0000000	-	120.	277	280	296	299	301	303	305	320	~_~	~10	20.	200	2.0
1	U	0000001	1	1298	194	218	219	247	248	278	310	324					
10	Ŭ	0000000A	1	1307	149	158	159	~ 1 '	~ 10	~ 10	010	0~1					
11	Ü	0000000A	1	1308	215	216	538	563	588	613	638	663	688	713	738	763	788
	· ·	000000 D		1000	813	838	863	888	913	938	963	991	1016	1041	1066	1091	1116
					1141	1166	1191	1216	1241	000	000	001	1010	1071	1000	1001	1110
12	U	000000C	1	1309	203	206	222	240	1~71								
13	Ü	0000000C	1	1310	~UJ	~UU	~~~	₽ŦU									
13 14	Ü	000000D 000000E	1	1310													
15	U	000000E	1	1311	231	256	283	284									
. 0 }	U	00000000	1	1299		259	260	267	268	276	279	280	297	299	205	306	207
	U	00000002	1	1299	195				200	210	219	۵ou	291	Lyy	305	300	307
	T T	0000000	4	1200	309	315	320	321									
3	U	00000003	1	1300													
1	U	00000004	1	1301	000	00~	010	0-~	000	F00	~ 40	~ 4 ~	-0-	F ~ ^	F 00		01-
5	U	00000005	1	1302	206	207	210	257	282	520	540	545	565	570	590	595	615
					620	640	645	665	670	690	695	715	720	740	745	765	770
					700	705	015	690	910	015	065	070	OUV	OUE	()15	920	940
					790 945	795 965	815 973	820 993	840 998	845 1018	865 1023	870 1043	890 1048	895 1068	915 1073	1093	1098

		REFEREN				or E7 VI										4: 28: 07		37
CHECK TTABLE RI_A	63 483	1255																
RI_A	442	518 943	543 971	568 996	593 1021	618 1046	643 1071	668 1096	693 1121	718 1146	743 1171	768 1196	793 1221	818	843	868	893	918



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STMI	FILE NAME	o de la companya de	
	O/sharedvfp/tests/zvector-e7-07-VGBM asm		
* NO ERRORS FOUN	I n **		
NO ERRORS FOUN	(D)		